


<b>Search Notes</b> 	<b>Application/Control No.</b> 10572595	<b>Applicant(s)/Patent Under Reexamination</b> YANO, KEIICHI
	<b>Examiner</b> MEIYA LI	<b>Art Unit</b> 2811

SEARCHED			
Class	Subclass	Date	Examiner
257	13,79,84,98,99,E25.019,E25.032,E33.056-E33.062,778,774,701,702	1/14,23/08	ML
438	FOR157,FOR287,FOR453,106,108	1/14,23/08	ML
313	501,512	1/14,23/08	ML
	updated	11/6/08	ML
	updated	5/15/09	ML

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	1/14,23/08	ML
updated	9/22/08, 11/6/08	ML
updated	5/15/09	ML

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner